

<b>Notice of References Cited</b>	Application/Control No. 10/583,195		Applicant(s)/Patent Under Reexamination DECOSTER, YVES	
	Examiner JONATHAN DUNLAP		Art Unit 2855	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,451,724 A	09-1995	Nakazawa et al.	178/18,05
*	B	US-5,965,856 A	10-1999	Okada et al.	200/85A
*	C	US-6,388,556 B1	05-2002	Imai et al.	338/114
*	D	US-6,450,046 B1	09-2002	Maeda, Tsutomu	73/862.473
*	E	US-6,774,331 B1	08-2004	Den Ridder et al.	200/512
*	F	US-6,829,942 B2	12-2004	Yanai et al.	73/754
*	G	US-6,875,938 B2	04-2005	Schmiz et al.	200/310
*	H	US-6,943,553 B2	09-2005	Zimmermann et al.	324/357
*	I	US-7,066,376 B2	06-2006	Scher et al.	228/175
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	Knight et al. "The Use of EIT Techniques to Measure Interface Pressure." Engineering in Medicine and Biology Society, 1990. Proceedings of the Twelfth Annual International Conference of the IEEE. 1-4 November 1990. Pages 2307-2308			
	V	Booth et al. "Comparing Electrode Configurations for Electrical Impedance Tomography." Electronics Letters. 28 March 1996. Vol. 32, Issue 7. Pages 648-649.			
	W	Booth et al. "Distributed Pressure Measurement Using Electrical Impedance Tomography: Initial Results." Advances in Electrical Tomography (Digest No: 1196/143), IEE Colloquium on. 19 June 1996. Pages 20/1-20/5			
	X				

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.